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| Notice of References Cited | Application/Control No. 09/997,774 | Applicant(s)/Patent Under Reexamination MUKHOPADHYAY ET AL. | |
| | Examiner Thien D. Tran | Art Unit 2665 | Page 1 of 1 |

U.S. PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Name | Classification |
|---|---|--|-----------------|------------------|----------------|
| | A | US-6,108,372 | 08-2000 | Tidemann et al. | 375/225 |
| | B | US-6,212,233 | 04-2001 | Alexandre et al. | 375/240.03 |
| | C | US-6,393,074 | 05-2002 | Mandyam et al. | 375/341 |
| | D | US-5,796,757 | 08-1998 | Czaja, Stash | 714/789 |
| | E | US-6,675,342 | 01-2004 | Yagyu, Mitsuhiko | 714/755 |
| | F | US-6,725,054 | 04-2004 | Hwang et al. | 455/522 |
| | G | US- | | | |
| | H | US- | | | |
| | I | US- | | | |
| | J | US- | | | |
| | K | US- | | | |
| | L | US- | | | |
| | M | US- | | | |

FOREIGN PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Country | Name | Classification |
|---|---|--|-----------------|---------|------|----------------|
| | N | | | | | |
| | O | | | | | |
| | P | | | | | |
| | Q | | | | | |
| | R | | | | | |
| | S | | | | | |
| | T | | | | | |

NON-PATENT DOCUMENTS

| * | | Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) |
|---|---|---|
| | U | |
| | V | |
| | W | |
| | X | |

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